

**Notice of References Cited**

Application/Control No.

101 611, 314

Applicant(s)/Patent Under  
Reexamination  
PEKAREK ET AL.

Examiner

Shambhavi Patel

Art Unit

2128

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0045843	11-2001	Hernandez-Marti, Ramon	326/30
*	B	US-6,642,741	11-2003	Metz et al.	326/30
*	C	US-6,985,698	01-2006	Aggarwal et al.	455/62
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Kim et al. 'Full Software Analysis and Impedance Matching of Radio Frequency CMOS Integrated Circuits'. Volume 23, March 2000. pages 183-189
*	V	Eo et al. "Generalized Coupled Interconnect Transfer Function and High-Speed Signal Simulations" IEEE Transactions of Microwave Theory and Techniques, Vol. 43 No. 5 May 1995.
*	W	Bockelman et al. "Combined Differential and Common-Mode Scattering Parameters: Theory and Simulation" IEEE Transactions on Microwave Theory and Techniques, Vol. 43 No. 7 July 1995.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.